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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/789,159	OCHIYA ET AL.	
Examiner	Art Unit	
Lora E. Barnhart	1651	

	SEARCHED		
Class	Subclass	Date	Examiner
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
USPATS, USPGPUBS (see EAST-search history)	4/13/2007	LEB
PALM inventor search	4/13/2007	LEB